

Search Notes



Application/Control No.		Applicant(s)/Patent under Reexamination		
	10/529,183	KONDO ET AL.		
	Examiner	Art Unit		
	Saw Eun Han	1772		

	SEARCHED		
Class	Subclass	Date	Examiner
428	1.25-1.26	12/27/2006	SH
349	126,135	·	
528	170,322		
	353,423		
	502F		-)
		•	
		-	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
0				
L				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST(USPGPUB;USPAT;USOCR;JPO; DERWENT) Text search history attached	12/27/2006	SH		
· · · · · · · · · · · · · · · · · · ·	·			